MANUFACTURER'S DECLARATION OF CONFORMITY

We:

ifm electronic gmbh
Friedrichstraße 1
45128 Essen, Germany

declare under our own responsibility that the product(s):

IO-Link Device "Laser Sensor"

O1D300
to which this declaration refers conform to:

☑  • IO-Link Interface and System Specification, V1.1, July 2013 (NOTE 1,2)
  • IO Device Description, V1.1, August 2011
☐  • IO-Link Interface and System Specification, V1.0, January 2009 (NOTE 1)
  • IO Device Description, V1.0.1, March 2010

The conformity tests are documented in the test report:
IO-Link Device Test Report 151698 O1D300 6 Okt 2017.pdf

Issued at  Tettnang, 6 Okt 2017

Authorized signatory
Name: Rolf Fensterle
Title: Product Development Manager
Signature: [Signature]

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NOTE 1 Relevant Test specification is V1.1, July 2014
NOTE 2 Additional validity in Corrigendum Package 2015
IO-Link Device Test Report 151698 O1D300 06 Okt 2017

Inhalt:

IO-Link Konformitätstest:
- Anhang

IO-Link Physiktest:
- Anhang
- Verweis: IO-Link Device Test Report 151698 O1D120 7 Apr 2017

IO-Link EMV-Test:

ESD (IEC 61000-4-2):
- Anhang
- Verweis: IO-Link Device Test Report 151698 O1D120 7 Apr 2017

HF gestrahlt (IEC 61000-4-3):
- Anhang
- Verweis: IO-Link Device Test Report 151698 O1D120 7 Apr 2017

Burst (IEC 61000-4-4):
- Anhang
- Verweis: IO-Link Device Test Report 151698 O1D120 7 Apr 2017

HF leitungsgebunden (IEC 61000-4-6):
- Anhang
- Verweis: IO-Link Device Test Report 151698 O1D120 7 Apr 2017
IO-Link Device Test Report

Device Test System Revision : 3.0.9.12 Build: 2015-11-6

Vendor: ifm electronic gmbh
Vendor ID : 0x0136
IO-Link Version : 1.1
ISDU supported : True
Process Data Input Bits : 64
Min Cycle Time : 5000 µs

Implemented Access Locks :
parameter="False" datastorage="True" localParameterization="True" localUserInterface="False"

IODD : ifm-00032D-20170926-IODD1.1.xml
Checker : IODD-Checker V1.1.1
Firmware Revision : 430

Device Name : O1D300
Device ID : 0x00032D
Product ID : O1D300
SIO mode supported : True
Process Data Output Bits : 0
Bitrate : COM2

CRC : 629177139
Hardware Revision : AK

Test result: All test were passed with positive result in complete operation

Test operated by: jfjyj

Postfach 62 83901 Tettnang
Tel. 07542/518-0 · Fax 07542/518-1290

Company: _________________________________
Name: _________________________________
Signature: _________________________________

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Testreport : Test Configuration

Test variable for 8 Bit index access:
- Index : 241
- Data (hex) : FE
- Length: 1

Test variable for 16 Bit index access:
- Index : 1000
- Data (hex) : 01
- Length: 1

Test variable for 8 Bit index extended length:
- Index : 24
- Length: 15
- Data (hex) : 31 32 33 34 35 36 37 38 39 41 42 43 44 45 46

Implemented system commands:
- 1
- 2
- 3
- 4
- 5
- 6
- 130
- 208
- 209
- 240
- 241
- 242
- 243
- M-sequence Capability (hex):
  - 2B

Commands to generate events:
- Event trigger 1 : appear value = 240, disappear value = 241
- Event trigger 2 : appear value = 242, disappear value = 243

Config Messages from Testcases

Testcase has skipped because the device is not capable to stimulate Process Data Error
Testreport Overview (1)

TC_Device Identification ok

support of Physical Layer Tests V1.0.3.11

Data Layer Tests V1.0.3.11

- SDCI_TC_0034 TCD_DLPC_STUP_CYCTIME ok
- SDCI_TC_0035 TCD_DLPC_STUP_STUPOPER1 ok
- SDCI_TC_0036 TCD_DLPC_STUP_STUPOPER2 ok
- SDCI_TC_0037 TCD_DLPC_OPER_OPERSTUP1 ok
- SDCI_TC_0038 TCD_DLPC_STAR_OPERSTAR2 ok
- SDCI_TC_0039 TCD_DLPC_PREO_READDPP1 ok
- SDCI_TC_0040 TCD_DLPC_PREO_WRITEDPP1 ok
- SDCI_TC_0041 TCD_DLPC_PROP_SHORT_FRAME ok
- SDCI_TC_0042 TCD_DLPC_PROP_WRITECOLL ok
- SDCI_TC_0043 TCD_DLPC_PROP_SIMRESET ok
- SDCI_TC_0044 TCD_DLPC_PROP_FRAMEFAULT ok
- SDCI_TC_0045 TCD_DLPC_OPER_READ ok
- SDCI_TC_0046 TCD_DLPC_OPER_READ ok
- SDCI_TC_0048 TCD_DLPC_OPER_WRITECOLL ok
- SDCI_TC_0049 TCD_DLPC_OPER_SIMRESET ok

ISDU Tests V1.0.3.11

- SDCI_TC_0052 TCD_DLPC_ISDU_AVALFSEQCAP ok
- SDCI_TC_0053 TCD_DLPC_ISDU_IDLEBUSYCHECK ok
- SDCI_TC_0054 TCD_DLPC_ISDU_READINDEX ok
- SDCI_TC_0055 TCD_DLPC_ISDU_READ8EXTLENGTH ok
- SDCI_TC_0056 TCD_DLPC_ISDU_WRITE8 ok
- SDCI_TC_0057 TCD_DLPC_ISDU_READ8RESERVED ok
- SDCI_TC_0058 TCD_DLPC_ISDU_READ8NOSUBINDEX ok
- SDCI_TC_0059 TCD_DLPC_ISDU_READ16 ok
- SDCI_TC_0060 TCD_DLPC_ISDU_WRITE16 ok
- SDCI_TC_0061 TCD_DLPC_ISDU_READ16RESERVED ok
- SDCI_TC_0062 TCD_DLPC_ISDU_READ16NOSUBINDEX ok
- SDCI_TC_0063 TCD_DLPC_ISDU_WRITE8LENERRORRUN ok
- SDCI_TC_0064 TCD_DLPC_ISDU_WRITE8WRONGLEN ok
- SDCI_TC_0065 TCD_DLPC_ISDU_WRITE8WRONGCHECKSUM ok
- SDCI_TC_0066 TCD_DLPC_ISDU_WRITE8ROINDEX ok
- SDCI_TC_0067 TCD_DLPC_ISDU_ABORTREADREQ ok
- SDCI_TC_0068 TCD_DLPC_ISDU_ABORTREADRESP ok

Event Tests V1.0.3.11

- SDCI_TC_0069 TCD_DLPC_EVNT_OPER_SINGLEEVENT ok
- SDCI_TC_0070 TCD_DLPC_EVNT_PROP_SINGLEEVENT ok
- SDCI_TC_0071 TCD_DLPC_EVNT_OPER_EVENTCLEAR ok
- SDCI_TC_0072 TCD_DLPC_EVNT_OPER_COMM_INTERRUPT ok
- SDCI_TC_0073 TCD_DLPC_EVNT_OPER_POWER_INTERRUPT ok
- SDCI_TC_0074 TCD_DLPC_EVNT_OPER_APPEAR_INSERT ok
- SDCI_TC_0075 TCD_DLPC_EVNT_OPER_MUTE_EVENT ok
- SDCI_TC_0076 TCD_DLPC_EVNT_OPER_SHORT_EVENT ok

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Testreport Overview (2)

Data Storage Tests V1.0.3.11
SDCI_TC_0077 TCD_APPS_DSUP_NOFLAG ok
SDCI_TC_0078 TCD_APPS_DSUP_VIADOWNLOADSTORE ok
SDCI_TC_0079 TCD_APPS_DSUP_VIADOWNLOADSTORENOWRITE ok
SDCI_TC_0080 TCD_APPS_DSUP_VIALOCALCHANGE ok
SDCI_TC_0081 TCD_APPS_DSUP_PARABREAKABORT ok
SDCI_TC_0082 TCD_APPS_DSDN_PARAMODIFICATION ok
SDCI_TC_0083 TCD_APPS_DSDN_FACTORYRESET ok
SDCI_TC_0084 TCD_APPS_DSDN_PARABREAKABORT ok

Legacy Master Tests V1.0.3.11
SDCI_TC_0085 TCD_DLIC_COMP_STARTUP ok
SDCI_TC_0086 TCD_DLIC_COMP_TYPE1_INTERLEAVE ok
SDCI_TC_0087 TCD_DLIC_COMP_PDINVALIDEVENT ok

Direct Parameter Page 1 Tests V1.0.3.11
SDCI_TC_0089 TCD_DLPC_STDP_MASTERCYCLETIME ok
SDCI_TC_0090 TCD_DLPC_STDP_MINCYCLETIME ok
SDCI_TC_0091 TCD_DLPC_STDP_FSEQCAPABILITY ok
SDCI_TC_0092 TCD_DLPC_STDP_REVISIONID ok
SDCI_TC_0093 TCD_DLPC_STDP_PDIN ok
SDCI_TC_0094 TCD_DLPC_STDP_PDOUT ok
SDCI_TC_0095 TCD_DLPC_STDP_VENDORID ok
SDCI_TC_0096 TCD_DLPC_STDP_DEVICEID ok
SDCI_TC_0097 TCD_DLPC_STDP_FUNCTIONID ok
SDCI_TC_0100 TCD_DLPC_STDP_READRESPAR ok
SDCI_TC_0101 TCD_DLPC_STDP_WRITERESPAR ok

Predefined Device Parameter Tests V1.0.3.11
SDCI_TC_0104 TCD_DLIC_DEFP_SYSCMDRES ok
SDCI_TC_0107 TCD_DLIC_DEFP_DSINDEX ok
SDCI_TC_0108 TCD_DLIC_DEFP_DSRECORD ok
SDCI_TC_0109 TCD_DLIC_DEFP_ACCESSLOCKSVAL ok
SDCI_TC_0110 TCD_DLIC_DEFP_ACCESSLOCKSINVAL ok
SDCI_TC_0111 TCD_DLIC_DEFP_PROFILCHARAC ok
SDCI_TC_0112 TCD_DLIC_DEFP_PDINDESC ok
SDCI_TC_0113 TCD_DLIC_DEFP_PDOUTDESC ok
SDCI_TC_0114 TCD_DLIC_DEFP_VENDORNAM ok
SDCI_TC_0115 TCD_DLIC_DEFP_VENDORTEXT ok
SDCI_TC_0116 TCD_DLIC_DEFP_PRODUCTNAM ok
SDCI_TC_0117 TCD_DLIC_DEFP_PRODUCTID ok
SDCI_TC_0118 TCD_DLIC_DEFP_PRODUCTTEXT ok
SDCI_TC_0119 TCD_DLIC_DEFP_SERNUM ok
SDCI_TC_0120 TCD_DLIC_DEFP_HARDREV ok
SDCI_TC_0121 TCD_DLIC_DEFP_FIRMREV ok
SDCI_TC_0122 TCD_DLIC_DEFP_TAGVALID ok
SDCI_TC_0123 TCD_DLIC_DEFP_TAGINVALID ok
SDCI_TC_0124 TCD_DLIC_DEFP_ERRCOUNT ok
Testreport Overview (3)

SDCI_TC_0128 TCD_DLIC_DEFP_DEVSTAT ok
SDCI_TC_0129 TCD_DLIC_DEFP_DETAILDEVSTAT ok
SDCI_TC_0130 TCD_DLIC_DEFP_DETAILDEVSTATINACTIVE ok
SDCI_TC_0131 TCD_DLIC_DEFP_DETAILDEVSTATACTIVE ok
SDCI_TC_0132 TCD_DLIC_DEFP_PDIN ok
SDCI_TC_0133 TCD_DLIC_DEFP_PDOUT ok
SDCI_TC_0134 TCD_DLIC_DEFP_OFFTIMEVALID ok
SDCI_TC_0135 TCD_DLIC_DEFP_OFFTIMEINVALID ok
SDCI_TC_0136 TCD_DLIC_DEFP_PROFILEPARREAD ok
SDCI_TC_0137 TCD_DLIC_DEFP_PROFILEPARWRITE ok
SDCI_TC_0140 TCD_DLIC_DEFP_WRITETOREADONLY ok
SDCI_TC_0141 TCD_DLIC_DEFP_WRITETOOSHORT ok
SDCI_TC_0142 TCD_DLIC_DEFP_WRITETOOLONG ok

Block Parameter Tests V1.0.3.11
SDCI_TC_0143 TCD_DSBP_APPL_BPDOWNLOAD ok
SDCI_TC_0144 TCD_DSBP_APPL_BPBREAKCMD ok
SDCI_TC_0145 TCD_DSBP_APPL_BPBREAKRESET ok
SDCI_TC_0147 TCD_DSBP_APPL_BPBREAK2DOWNLOADS ok
SDCI_TC_0148 TCD_DSBP_APPL_BPBREAKLOCALLOCK ok

IODD based Tests V1.0.3.11
SDCI_TC_0149 TCD_JODD_PARV_IDENT ok
SDCI_TC_0150 TCD_JODD_PARV_COMPROFILE ok
SDCI_TC_0151 TCD_JODD_PARV_READVERIFY ok
SDCI_TC_0152 TCD_JODD_PARV_WRITEVERIFY ok
SDCI_TC_0155 TCD_JODD_PARV_FACTORYSETTINGS ok
SDCI_TC_0156 TCD_JODD_PARV_ACCESSLOCK ok
SDCI_TC_0157 TCD_JODD_PARV_INDEXCONSISTENT ok

Test Report Statistics:

Number of test cases overall : 107
Number of test cases ok : 107
Number of test cases failed : 0
Number of test cases skipped : 0
Test Operation : complete